

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination ALBECK ET AL.	
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U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U XP000466818: Sansoni, G., et al., "A Novel, Adaptive System for 3-D Optical Profilometry Using A Liquid Crystal Light Projector", IEEE TRANSACTION ON INSTRUMENTATION AND MEASUREMENT, IEEE INC., Vol. 43, AO No. 4, pages 558-565, (1994).
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